

### **REMARKS**

At the time of the present Official Action, claims 1-69 were pending. The Examiner rejected claims 1-7, 35-42, and 53-59, objected to claims 8-17, 43-52, and 60-69, and allowed claims 18-34. Although Applicant does not agree with the rejection of claims 1-7, 35-42, and 53-59, Applicant has chosen to place the present application in condition for allowance. Accordingly, Applicant has cancelled claims 8, 43, and 60 to include the allowable subject matter in each of these claims into the respective independent claims 1, 35, and 53. Applicant respectfully requests that the Examiner pass the above-referenced application to issue with claims 1-7, 9-42, 44-59, and 61-69.

### **Allowable Subject Matter**


If the Examiner believes that a telephonic interview will help speed this application toward issuance, the Examiner is invited to contact the undersigned at the telephone number below. Attached hereto as an Appendix is a clean version of the changes made by the current amendment.

**General Authorization for Extensions of Time**

In accordance with 37 C.F.R. § 1.136, Applicant hereby provides a general authorization to treat this and any future reply requiring an extension of time as incorporating a request thereof. Furthermore, Applicant authorizes the Commissioner to charge the appropriate fee for any extension of time to Deposit Account No. 13-3092; Order No. MICS:0060/FLE (00-0731).

Respectfully submitted,

Date: May 13, 2003

  
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## APPENDIX

1. (Once amended) An integrated circuit comprising:

a programmable element located on the integrated circuit, the programmable element being coupled to a redundant circuit used to repair the integrated circuit; and

a source located on the integrated circuit and comprising a flyback pump, the source adapted to be operatively coupled to the programmable element and to develop a programming signal sufficient to program the programmable element to activate the redundant circuit.

9. (Once amended) The integrated circuit, as set forth in claim 1, wherein the flyback pump comprises:

an inductance;

a control circuit coupled to the inductance to control energizing the inductance; and

an output circuit coupled to the inductance to deliver the programming signal from the inductance to the programmable element.

35. (Once amended) A system comprising:

a processor;

a memory device operably coupled to the processor, the memory device comprising:

a programmable element located on the memory device, the programmable element being

coupled to a redundant row or column used to repair the memory device; and

a source located on the memory device and comprising a flyback pump, the source

adapted to develop and deliver a programming signal sufficient to program the

programmable element to activate the redundant row or column in response to the

processor indicating that a memory location of the memory device is non-

functional.

39. (Once amended) The system, as set forth in claim 35, wherein the memory device comprises a plurality of programmable elements, each of the plurality of programmable elements being coupled to a respective redundant row or column.

44. (Once amended) The system, as set forth in claim 35, wherein the flyback pump comprises:

an inductance;

a control circuit coupled to the inductance to control energizing the inductance; and

an output circuit coupled to the inductance to deliver the programming signal from the inductance to the programmable element.

53. (Once amended) An integrated circuit testing apparatus comprising:

an integrated circuit;

a testing device configured to couple to the integrated circuit and to functionally test at least one target circuit of the integrated circuit, wherein the integrated circuit comprises:

a programmable element located on the integrated circuit, the programmable element being coupled to redundant circuitry used to repair the integrated circuit; and

a source located on the integrated circuit and comprising a flyback pump, the source adapted to be operatively coupled to the programmable element and to develop a programming signal sufficient to program the programmable element to activate the redundant circuitry in response to the testing device indicating that the target circuit is at least partially non-functional.

61. (Once amended) The apparatus, as set forth in claim 53, wherein the flyback pump comprises:

an inductance;

a control circuit coupled to the inductance to control energizing the inductance; and

an output circuit coupled to the inductance to deliver the programming signal from the inductance to the programmable element.